

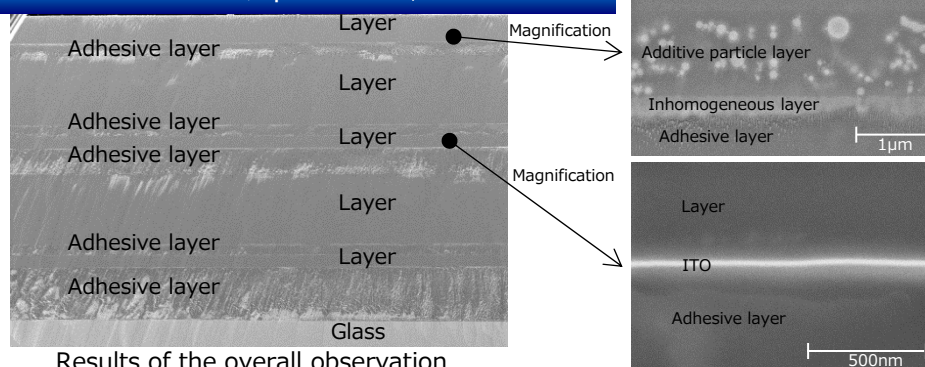
Evaluation of peripheral components of display panels

For display panels, higher specifications are needed not only in the structure of display parts but also in the peripheral parts (sealing, planarization layer, wiring, optical film, touch panel etc.). The analytic menu and SEM observation example are shown below.

Evaluation menu for the peripheral components of panel

| Items for evaluation | Analysis items and purposes | Applicable methods |
|---|---|---|
| Evaluation of optical film and touch panel | | |
| Film, Adhesives, Sealing agents | Analysis of composition and structure | IR, NMR, MS, PyGC/MS, fluorescent X-ray, TOF-SIMS |
| | Measurement of trace additives | Preparation of GPCs + (IR, NMR, MS), HPLC-UV, HPLC-ELSD, LC/MS, GC, GC/MS, etc. |
| | Higher-order structural analysis (orientation and crystallinity) | IR, Raman, X-ray diffractometry |
| | Optical properties (refractive index, absorbance, reflectance) | Spectral ellipsometer, Spectrophotometer |
| | Thermal property | DSC, TMA (thermal expansion coefficient measurement) |
| | Moisture adsorption and permeation measurements | Measurements of water vapor/gas adsorption, Mocon method, TPD-MS |
| | Depth profile analysis | GD-OES, SIMS |
| | Morphological observation | SEM/EDX |
| Touch-panel | Morphological observation and compositional evaluation | SEM/EDX, TEM/AEM |
| Peripheral parts evaluation of pixel | | |
| TFT | Morphological observation, impurity evaluation, and dopant distribution | TEM, SIMS, TOF-SIMS, SCM, SSRM |
| Oriented film CF, Planarizing film, Sealing film | Compositional analysis, orientational evaluation, and foreign matter (repellency) | IR, TOF-SIMS, NMR, PyGC/MS, SEM |
| | Pigment identification | Raman, IR |
| | Heated gas | GC/MS, TPD-MS |
| Seal evaluation | | |
| Mold resin | Morphological observation and compositional analysis | SEM/EDX, IR, PyGC/MS |
| Sealing glass | Morphological observation and compositional analysis | SEM/EDX |
| Sealing film | Morphological observation and compositional analysis | SEM, SIMS, RBS, IR, NMR, MS, PyGC/MS, fluorescent X-ray |
| Filler gas | Identification of gas type and water content | TPD-MS, sealing assessment (isotopic marker method) |

SEM Observation (Optical Film, Touch Panel)



From the overall observation results in the left figure, five layers (excluding the adhesive layer) can be seen and a layer containing additive particles and a stack with transparent electrode is also found.

Results of the overall observation